E.J. Lattice Semiconductor Corporation - <u>LFE5U-45F-6BG381I Datasheet</u>



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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	11000
Number of Logic Elements/Cells	44000
Total RAM Bits	1990656
Number of I/O	203
Number of Gates	
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	381-FBGA
Supplier Device Package	381-CABGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5u-45f-6bg381i

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1. General Description

The ECP5/ECP5-5G family of FPGA devices is optimized to deliver high performance features such as an enhanced DSP architecture, high speed SERDES (Serializer/Deserializer), and high speed source synchronous interfaces, in an economical FPGA fabric. This combination is achieved through advances in device architecture and the use of 40 nm technology making the devices suitable for high-volume, highspeed, and low-cost applications.

The ECP5/ECP5-5G device family covers look-up-table (LUT) capacity to 84K logic elements and supports up to 365 user I/Os. The ECP5/ECP5-5G device family also offers up to 156 18 x 18 multipliers and a wide range of parallel I/O standards.

The ECP5/ECP5-5G FPGA fabric is optimized high performance with low power and low cost in mind. The ECP5/ ECP5-5G devices utilize reconfigurable SRAM logic technology and provide popular building blocks such as LUT-based logic, distributed and embedded memory, Phase-Locked Loops (PLLs), Delay-Locked Loops (DLLs), pre-engineered source synchronous I/O support, enhanced sysDSP slices and advanced configuration support, including encryption and dual-boot capabilities.

The pre-engineered source synchronous logic implemented in the ECP5/ECP5-5G device family supports a broad range of interface standards including DDR2/3, LPDDR2/3, XGMII, and 7:1 LVDS.

The ECP5/ECP5-5G device family also features high speed SERDES with dedicated Physical Coding Sublayer (PCS) functions. High jitter tolerance and low transmit jitter allow the SERDES plus PCS blocks to be configured to support an array of popular data protocols including PCI Express, Ethernet (XAUI, GbE, and SGMII) and CPRI. Transmit De-emphasis with pre- and post-cursors, and Receive Equalization settings make the SERDES suitable for transmission and reception over various forms of media.

The ECP5/ECP5-5G devices also provide flexible, reliable and secure configuration options, such as dual-boot capability, bit-stream encryption, and TransFR field upgrade features.

ECP5-5G family devices have made some enhancement in the SERDES compared to ECP5UM devices. These enhancements increase the performance of the SERDES to up to 5 Gb/s data rate.

The ECP5-5G family devices are pin-to-pin compatible with the ECP5UM devices. These allows a migration path for users to port designs from ECP5UM to ECP5-5G devices to get higher performance. The Lattice Diamond[™] design software allows large complex designs to be efficiently implemented using the ECP5/ECP5-5G FPGA family. Synthesis library support for ECP5/ECP5-5G devices is available for popular logic synthesis tools. The Diamond tools use the synthesis tool output along with the constraints from its floor planning tools to place and route the design in the ECP5/ECP5-5G device. The tools extract the timing from the routing and back-annotate it into the design for timing verification.

Lattice provides many pre-engineered IP (Intellectual Property) modules for the ECP5/ECP5-5G family. By using these configurable soft core IPs as standardized blocks, designers are free to concentrate on the unique aspects of their design, increasing their productivity.

1.1. Features

- Higher Logic Density for Increased System Integration
 - 12K to 84K LUTs
 - 197 to 365 user programmable I/Os
- Embedded SERDES
 - 270 Mb/s, up to 3.2 Gb/s, SERDES interface (ECP5)
 - 270 Mb/s, up to 5.0 Gb/s, SERDES interface (ECP5-5G)
 - Supports eDP in RDR (1.62 Gb/s) and HDR (2.7 Gb/s)
 - Up to four channels per device: PCI Express, Ethernet (1GbE, SGMII, XAUI), and CPRI
- sysDSP™
 - Fully cascadable slice architecture
 - 12 to 160 slices for high performance multiply and accumulate
 - Powerful 54-bit ALU operations
 - Time Division Multiplexing MAC Sharing
 - Rounding and truncation
 - Each slice supports
 - Half 36 x 36, two 18 x 18 or four 9 x 9 multipliers
 - Advanced 18 x 36 MAC and 18 x 18 Multiply-Multiply-Accumulate (MMAC) operations
- Flexible Memory Resources
 - Up to 3.744 Mb sysMEM[™] Embedded Block RAM (EBR)
 - 194K to 669K bits distributed RAM
- sysCLOCK Analog PLLs and DLLs



2.3. Routing

There are many resources provided in the ECP5/ECP5-5G devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments.

The ECP5/ECP5-5G family has an enhanced routing architecture that produces a compact design. The Diamond design software tool suites take the output of the synthesis tool and places and routes the design.

2.4. Clocking Structure

ECP5/ECP5-5G clocking structure consists of clock synthesis blocks (sysCLOCK PLL); balanced clock tree networks (PCLK and ECLK trees); and efficient clock logic modules (CLOCK DIVIDER and Dynamic Clock Select (DCS), Dynamic Clock Control (DCC) and DLL). All of these functions are described below.

2.4.1. sysCLOCK PLL

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The devices in the ECP5/ECP5-5G family support two to four full-featured General Purpose PLLs. The sysCLOCK PLLs provide the ability to synthesize clock frequencies.

The architecture of the PLL is shown in Figure 2.5. A description of the PLL functionality follows.

CLKI is the reference frequency input to the PLL and its source can come from two different external CLK inputs or from internal routing. A non-glitchless 2-to-1 input multiplexor is provided to dynamically select between two different external reference clock sources. The CLKI input feeds into the input Clock Divider block.

CLKFB is the feedback signal to the PLL which can come from internal feedback path, routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The PLL has four clock outputs CLKOP, CLKOS, CLKOS2 and CLKOS3. Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the primary clock network. Only CLKOP and CLKOS outputs can go to the edge clock network.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock. This phase shift can be either programmed during configuration or can be adjusted dynamically using the PHASESEL, PHASEDIR, PHASESTEP, and PHASELOADREG ports.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected.







Table 2.6. sysMEM Block Configurations

Memory Mode	Configurations			
	16,384 x 1			
	8,192 x 2			
Single Port	4,096 x 4			
	2,048 x 9			
	1,024 x 18			
	512 x 36			
	16,384 x 1			
	8,192 x 2			
True Dual Port	4,096 x 4			
	2,048 x 9			
	1,024 x 18			
	16,384 x 1			
	8,192 x 2			
Decudo Dual Dort	4,096 x 4			
PSeudo Dual Port	2,048 x 9			
	1,024 x 18			
	512 x 36			

2.8.2. Bus Size Matching

All of the multi-port memory modes support different widths on each of the ports. The RAM bits are mapped LSB word 0 to MSB word 0, LSB word 1 to MSB word 1, and so on. Although the word size and number of words for each port varies, this mapping scheme applies to each port.

2.8.3. RAM Initialization and ROM Operation

If desired, the contents of the RAM can be pre-loaded during device configuration. By preloading the RAM block during the chip configuration cycle and disabling the write controls, the sysMEM block can also be utilized as a ROM.

2.8.4. Memory Cascading

Larger and deeper blocks of RAM can be created using EBR sysMEM Blocks. Typically, the Lattice design tools cascade memory transparently, based on specific design inputs.

2.8.5. Single, Dual and Pseudo-Dual Port Modes

In all the sysMEM RAM modes the input data and address for the ports are registered at the input of the memory array. The output data of the memory is optionally registered at the output.

EBR memory supports the following forms of write behavior for single port or dual port operation:

- **Normal** Data on the output appears only during a read cycle. During a write cycle, the data (at the current address) does not appear on the output. This mode is supported for all data widths.
- Write Through A copy of the input data appears at the output of the same port during a write cycle. This mode is supported for all data widths.
- **Read-Before-Write** When new data is written, the old content of the address appears at the output. This mode is supported for x9, x18, and x36 data widths.

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*For 7:1 LVDS interface only. It is required to use PIO pair pins PIOA/B.

Figure 2.20. Output Register Block on Left and Right Sides

Name	Туре	Description
Q	Output	High Speed Data Output
D	Input	Data from core to output SDR register
D[1:0]/D[3:0]/ D[6:0]	Input	Low Speed Data from device core to output DDR register
RST	Input	Reset to the Output Block
SCLK	Input	Slow Speed System Clock
ECLK	Input	High Speed Edge Clock
DQSW	Input	Clock from DQS control Block used to generate DDR memory DQS output
DQSW270	Input	Clock from DQS control Block used to generate DDR memory DQ output

Table 2.9. Output Block Port Description

2.12. Tristate Register Block

The tristate register block registers tristate control signals from the core of the device before they are passed to the sysIO buffers. The block contains a register for SDR operation. In SDR, TD input feeds one of the flip-flops that then feeds the output. In DDR operation used mainly for DDR memory interface can be implemented on the left and right sides of the device. Here two inputs feed the tristate registers clocked by both ECLK and SCLK.

Figure 2.21 and Figure 2.22 show the Tristate Register Block functions on the device. For detailed description of the tristate register block modes and usage, refer to ECP5 and ECP5-5G High-Speed I/O Interface (TN1265).



Figure 2.21. Tristate Register Block on Top Side







Name	Туре	Description
TD	Input	Tristate Input to Tristate SDR Register
RST	Input	Reset to the Tristate Block
TD[1:0]	Input	Tristate input to TSHX2 function
SCLK	Input	Slow Speed System Clock
ECLK	Input	High Speed Edge Clock
DQSW	Input	Clock from DQS control Block used to generate DDR memory DQS output
DQSW270	Input	Clock from DQS control Block used to generate DDR memory DQ output
TQ	Output	Output of the Tristate block

2.13. DDR Memory Support

2.13.1. DQS Grouping for DDR Memory

Certain PICs have additional circuitry to allow the implementation of high-speed source synchronous and DDR2, DDR3, LPDDR2 or LPDDR3 memory interfaces. The support varies by the edge of the device as detailed below.

The left and right sides of the PIC have fully functional elements supporting DDR2, DDR3, LPDDR2 or LPDDR3 memory interfaces. Every 16 PIOs on the left and right sides are grouped into one DQS group, as shown in Figure 2.23 on page 36. Within each DQS group, there are two pre-placed pins for DQS and DQS# signals. The rest of the pins in the DQS group can be used as DQ signals and DM signal. The number of pins in each DQS group bonded out is package dependent. DQS groups with less than 11 pins bonded out can only be used for LPDDR2/3 Command/ Address busses. In DQS groups with more than 11 pins bonded out, up to two pre-defined pins are assigned to be used as "virtual" VCCIO, by driving these pins to HIGH, with the user connecting these pins to VCCIO power supply. These connections create "soft" connections to V_{CCIO} thru these output pins, and make better connections on VCCIO to help to reduce SSO noise. For details, refer to ECP5 and ECP5-5G High-Speed I/O Interface (TN1265).



3.7. Hot Socketing Requirements

Table 3.6. Hot Socketing Requirements

Description	Min	Тур	Max	Unit
Input current per SERDES I/O pin when device is powered down and inputs driven.	_	_	8	mA
Input current per HDIN pin when device power supply is off, inputs driven ^{1, 2}	_	_	15	mA
Current per HDIN pin when device power ramps up, input driven ³	—	—	50	mA
Current per HDOUT pin when device power supply is off, outputs pulled up ⁴	_	_	30	mA

Notes:

1. Device is powered down with all supplies grounded, both HDINP and HDINN inputs driven by a CML driver with maximum allowed output V_{CCHTX}, 8b/10b data, no external AC coupling.

2. Each P and N input must have less than the specified maximum input current during hot plug. For a device with 2 DCU, the total input current would be 15 mA * 4 channels * 2 input pins per channel = 120 mA.

- Device power supplies are ramping up (V_{CCA} and V_{CCAUX}), both HDINP and HDINN inputs are driven by a CML driver with maximum allowed output V_{CCHTX}, 8b/10b data, internal AC coupling.
- 4. Device is powered down with all supplies grounded. Both HDOUTP and HDOUN outputs are pulled up to V_{CCHTX} by the far end receiver termination of 50 Ω single ended.

3.8. ESD Performance

Refer to the ECP5 and ECP5-5G Product Family Qualification Summary for complete qualification data, including ESD performance.

3.9. DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min	Тур	Max	Unit
I _{IL} , I _{IH} ^{1, 4}	Input or I/O Low Leakage	$0 \leq V_{IN} \leq V_{CCIO}$	—	_	10	μA
I _{IH} ^{1, 3}	Input or I/O High Leakage	$V_{CCIO} < V_{IN} \le V_{IH(MAX)}$	—	_	100	μA
1	I/O Active Pull-up Current, sustaining logic HIGH state	$0.7 \ V_{CCIO} \! \leq \! V_{IN} \! \leq \! V_{CCIO}$	-30	_	_	μA
160	I/O Active Pull-up Current, pulling down from logic HIGH state	$0 \leq V_{\text{IN}} \leq 0.7 \ V_{\text{CCIO}}$	_	_	-150	μA
las	I/O Active Pull-down Current, sustaining logic LOW state	$0 \le V_{IN} \le V_{IL}$ (MAX)	30	_	_	μΑ
IPD	I/O Active Pull-down Current, pulling up from logic LOW state	$0 \leq V_{\text{IN}} \leq V_{\text{CCIO}}$	—	—	150	μA
C1	I/O Capacitance ²	$\begin{split} V_{CCIO} &= 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V}, \\ V_{CC} &= 1.2 \text{ V}, \text{ V}_{IO} &= 0 \text{ to } ^{V_{IH(MAX)}} \end{split}$	_	5	8	pf
C2	Dedicated Input Capacitance ²	$V_{CCIO} = 3.3 \text{ V}, 2.5 \text{ V}, 1.8 \text{ V}, 1.5 \text{ V}, 1.2 \text{ V}, \\ V_{CC} = 1.2 \text{ V}, V_{IO} = 0 \text{ to } V_{\text{IH}(\text{MAX})}$	_	5	7	pf
N	Hysteresis for Single-Ended	V _{CCIO} = 3.3 V	—	300	—	mV
V HYST	Inputs	V _{CCI0} = 2.5 V	_	250	_	mV

Table 3.7. DC Electrical Characteristics

Notes:

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tristated. It is not measured with the output driver active. Bus maintenance circuits are disabled.

2. T_A 25 °C, f = 1.0 MHz.

- 3. Applicable to general purpose I/Os in top and bottom banks.
- 4. When used as V_{REF} , maximum leakage= 25 μ A.



Table 3.10. ECP5-5G

Symbol	Description	Тур	Max	Unit
Standby (Power	Down)			
I _{CCA-SB}	V _{CCA} Power Supply Current (Per Channel)	4	9.5	mA
I _{CCHRX-SB} ⁴	V _{CCHRX} , Input Buffer Current (Per Channel)	_	0.1	mA
I _{CCHTX-SB}	V _{CCHTX} , Output Buffer Current (Per Channel)	_	0.9	mA
Operating (Data	Rate = 5 Gb/s)			
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	58	67	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data	Rate = 3.2 Gb/s)			
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	48	57	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data	Rate = 2.5 Gb/s)			
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	44	53	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data	Rate = 1.25 Gb/s)			
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	36	46	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	10	13	mA
Operating (Data	Rate = 270 Mb/s)			
I _{CCA-OP}	V _{CCA} Power Supply Current (Per Channel)	30	40	mA
I _{CCHRX-OP} ⁵	V _{CCHRX} , Input Buffer Current (Per Channel)	0.4	0.5	mA
I _{CCHTX-OP}	V _{CCHTX} , Output Buffer Current (Per Channel)	8	10	mA

Notes:

1. Rx Equalization enabled, Tx De-emphasis (pre-cursor and post-cursor) disabled

2. Per Channel current is calculated with both channels on in a Dual, and divide current by two. If only one channel is on, current will be higher.

3. To calculate with Tx De-emphasis enabled, use the Diamond Power Calculator tool.

4. For ICCHRX-SB, during Standby, input termination on Rx are disabled.

5. For ICCHRX-OP, during operational, the max specified when external AC coupling is used. If externally DC coupled, the power is based on current pulled down by external driver when the input is driven to LOW.



Table 3.22. ECP5/ECP5-5G External Switching Characteristics (Continued)

Demonstern	Description	Device	-	-8	-	-7	-	-6	11
Parameter			Min	Max	Min	Max	Min	Max	Unit
Generic DDR Output									
Generic DDRX1 Outputs With Clock and Data Centered at Pin (GDDRX1 TX.SCLK.Centered) Using PCLK Clock Input - Figure 3.6									
t _{DVB_GDDRX1_centered}	Data Output Valid before CLK Output	All Devices	-0.67	_	-0.67	-	-0.67	_	ns + 1/2 UI
t _{DVA_GDDRX1_centered}	Data Output Valid after CLK Output	All Devices	-0.67	_	-0.67	-	-0.67	-	ns + 1/2 UI
f _{DATA_GDDRX1_centered}	GDDRX1 Data Rate	All Devices	_	500	-	500	—	500	Mb/s
f _{MAX_GDDRX1_centered}	GDDRX1 CLK Frequency (SCLK)	All Devices	—	250	—	250	—	250	MHz
Generic DDRX1 Ou	tputs With Clock and Data Aligne	ed at Pin (GDD	RX1_TX.9	SCLK.Alig	ned) Usin	g PCLK C	lock Inpu	t - Figure	3.9
t _{DIB_GDDRX1_aligned}	Data Output Invalid before CLK Output	All Devices	-0.3	_	-0.3	_	-0.3	_	ns
$t_{\text{DIA}_\text{GDDRX1}_\text{aligned}}$	Data Output Invalid after CLK Output	All Devices	_	0.3	_	0.3	-	0.3	ns
$f_{DATA_GDDRX1_aligned}$	GDDRX1 Data Rate	All Devices	—	500	—	500	—	500	Mb/s
$f_{MAX_GDDRX1_aligned}$	GDDRX1 CLK Frequency (SCLK)	All Devices	_	250	—	250	—	250	MHz
Generic DDRX2 Ou	tputs With Clock and Data Cente	red at Pin (GD	DRX2_TX	.ECLK.Ce	ntered) l	Jsing PCL	K Clock Iı	nput, Left	and
Right sides Only - F	igure 3.8			1		1	1		
$t_{\text{DVB}_{GDDRX2}_{centered}}$	Data Output Valid Before CLK Output	All Devices	- 0.442	—	-0.56	-	– 0.676	_	ns + 1/2 UI
$t_{\text{DVA}_{GDDRX2}_{centered}}$	Data Output Valid After CLK Output	All Devices	—	0.442	_	0.56	_	0.676	ns + 1/2 UI
$f_{DATA_GDDRX2_centered}$	GDDRX2 Data Rate	All Devices	_	800		700	—	624	Mb/s
$f_{MAX_GDDRX2_centered}$	GDDRX2 CLK Frequency (ECLK)	All Devices	_	400	-	350	—	312	MHz
Generic DDRX2 Ou	tputs With Clock and Data Aligne	d at Pin (GDD	RX2_TX.I	ECLK.Alig	ned) Usin	g PCLK C	lock Inpu	t, Left an	d Right
sides Only - Figure	3.9			1	1	1	1	i.	1
$t_{DIB_GDDRX2_aligned}$	CLK Output	All Devices	-0.16	_	-0.18	_	-0.2	_	ns
$t_{\text{DIA}_{GDDRX2}_{aligned}}$	Data Output Invalid after CLK Output	All Devices	_	0.16	-	0.18	-	0.2	ns
$f_{DATA_GDDRX2_aligned}$	GDDRX2 Data Rate	All Devices	—	800		700	—	624	Mb/s
$f_{MAX_GDDRX2_aligned}$	GDDRX2 CLK Frequency (ECLK)	All Devices	—	400	—	350	—	312	MHz
Video DDRX71 Out	puts With Clock and Data Aligne	d at Pin (GDDF	х71_тх.	ECLK) Us	ing PLL Cl	ock Input	t, Left an	d Right si	des Only
- Figure 3.12					1	1	1	1	
t _{dib_lvds71_i}	Data Output Invalid before CLK Output	All Devices	-0.16	—	-0.18	_	-0.2		ns + (i) * UI
t _{dia_lvds71_i}	Data Output Invalid after CLK Output	All Devices	—	0.16	_	0.18	_	0.2	ns + (i) * UI
f _{data_lvds71}	DDR71 Data Rate	All Devices	_	756	—	620	—	525	Mb/s
f _{MAX_LVDS71}	DDR71 CLK Frequency (ECLK)	All Devices	_	378	—	310	—	262.5	MHz
Memory Interface									
DDR2/DDR3/DDR3	L/LPDDR2/LPDDR3 READ (DQ Inj	put Data are A	ligned to	DQS)					
t _{dvbdq_ddr2}									
t _{dvbdq_ddr3}	Data Output Valid before DQS					_		_	ns + 1/2
t _{DVBDQ_DDR3L}	Input	All Devices	_	-0.26	_	0.317	_	0.374	U
LDVBDQ_LPDDR2									
UVADQ_DDR2									
tovado ddral	Data Output Valid after DQS	All Devices	0.26	_	0.317	_	0.374	_	ns + 1/2
t _{DVADQ_LPDDR2}	Input								UI
t _{dvadq_lpddr3}									

Table 3.22. ECP5/ECP5-5G External Switching Characteristics (Continued)





Figure 3.6. Receiver RX.CLK.Centered Waveforms



Figure 3.7. Receiver RX.CLK.Aligned and DDR Memory Input Waveforms



Figure 3.8. Transmit TX.CLK.Centered and DDR Memory Output Waveforms

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3.25. PCI Express Electrical and Timing Characteristics

3.25.1. PCIe (2.5 Gb/s) AC and DC Characteristics

Over recommended operating conditions.

Table 3.30. PCIe (2.5 Gb/s)

Symbol	Description	Test Conditions	Min	Тур	Max	Unit		
Transmit ¹								
UI	Unit interval	_	399.88	400	400.12	ps		
V _{TX-DIFF_P-P}	Differential peak-to-peak output	—	0.8	1.0	1.2	V		
V _{TX-DE-RATIO}	De-emphasis differential output voltage ratio	_	-3	-3.5	-4	dB		
V _{TX-CM-AC_P}	RMS AC peak common-mode output voltage	_	_	_	20	mV		
V _{TX-RCV-DETECT}	Amount of voltage change allowed during receiver detection	_	_	_	600	mV		
V _{TX-CM-DC}	Tx DC common mode voltage	_	0	_	V _{CCHTX}	V		
I _{TX-SHORT}	Output short circuit current	V _{TX-D+} =0.0 V V _{TX-D-} =0.0 V	_	_	90	mA		
Z _{TX-DIFF-DC}	Differential output impedance	—	80	100	120	Ω		
RL _{TX-DIFF}	Differential return loss	—	10	_	—	dB		
RL _{TX-CM}	Common mode return loss	—	6.0	_	—	dB		
T _{TX-RISE}	Tx output rise time	20% to 80%	0.125	_	—	UI		
T _{TX-FALL}	Tx output fall time	20% to 80%	0.125	_	—	UI		
L _{TX-SKEW}	Lane-to-lane static output skew for all lanes in port/link	-	-	-	1.3	ns		
T _{TX-EYE}	Transmitter eye width	—	0.75	_	—	UI		
T _{TX-EYE-MEDIAN-TO-MAX-} JITTER	Maximum time between jitter median and maximum deviation from median	-	-	-	0.125	UI		
Receive ^{1, 2}								
UI	Unit Interval	_	399.88	400	400.12	ps		
V _{RX-DIFF_P-P}	Differential peak-to-peak input voltage	_	0.34 ³	_	1.2	v		
V _{RX-IDLE-DET-DIFF_P-P}	Idle detect threshold voltage	_	65	—	340 ³	mV		
V _{RX-CM-AC_P}	RMS AC peak common-mode input voltage	_	_	_	150	mV		
Z _{RX-DIFF-DC}	DC differential input impedance	_	80	100	120	Ω		
Z _{RX-DC}	DC input impedance	_	40	50	60	Ω		
Z _{RX-HIGH-IMP-DC}	Power-down DC input impedance	_	200K	—	-	Ω		
RL _{RX-DIFF}	Differential return loss	_	10	—	-	dB		
RL _{RX-CM}	Common mode return loss	-	6.0	—	—	dB		

Notes:

- 1. Values are measured at 2.5 Gb/s.
- 2. Measured with external AC-coupling on the receiver.
- 3. Not in compliance with PCI Express 1.1 standard.

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3.25.2. PCIe (5 Gb/s) – Preliminary AC and DC Characteristics

Over recommended operating conditions.

Table 3.31. PCIe (5 Gb/s)

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
Transmit ¹						
UI	Unit Interval	—	199.94	200	200.06	ps
B _{WTX-PKG-PLL2}	Tx PLL bandwidth corresponding to PKGTX-PLL2	-	5	_	16	MHz
P _{KGTX-PLL2}	Tx PLL Peaking	-	_	—	1	dB
V _{TX-DIFF-PP}	Differential p-p Tx voltage swing	-	0.8	—	1.2	V, p-р
V _{TX-DIFF-PP-LOW}	Low power differential p-p Tx voltage swing	-	0.4	_	1.2	V, p-p
V _{TX-DE-RATIO-3.5dB}	Tx de-emphasis level ratio at 3.5dB	-	3	—	4	dB
V _{TX-DE-RATIO-6dB}	Tx de-emphasis level ratio at 6dB	-	5.5	—	6.5	dB
T _{MIN-PULSE}	Instantaneous lone pulse width	_		_	_	UI
T _{TX-RISE-FALL}	Transmitter rise and fall time	_		_	_	UI
T _{TX-EYE}	Transmitter Eye, including all jitter sources	_	0.75	_	_	UI
T _{TX-DJ}	Tx deterministic jitter > 1.5 MHz	_	_	_	0.15	UI
T _{TX-RJ}	Tx RMS jitter < 1.5 MHz	-	-	_	3	ps, RMS
T _{RF-MISMATCH}	Tx rise/fall time mismatch	-	_	—		UI
B	Tx Differential Return Loss, including	50 MHz < freq < 1.25 GHz	10	_	_	dB
INLTX-DIFF	package and silicon	1.25 GHz < freq < 2.5 GHz	8	_	_	dB
R _{LTX-CM}	Tx Common Mode Return Loss, including package and silicon	50 MHz < freq < 2.5 GHz	6	_	-	dB
Z _{TX-DIFF-DC}	DC differential Impedance	-	_	—	120	Ω
V _{TX-CM-AC-PP}	Tx AC peak common mode voltage, peak-peak	-	-	—		mV, p-p
I _{TX-SHORT}	Transmitter short-circuit current	_	_	_	90	mA
V _{TX-DC-CM}	Transmitter DC common-mode voltage	_	0	_	1.2	v
V _{TX-IDLE-DIFF-DC}	Electrical Idle Output DC voltage	-	0	_	5	mV
V _{TX-IDLE-DIFF-AC-p}	Electrical Idle Differential Output peak voltage	_	_	_		mV
V _{TX-RCV-DETECT}	Voltage change allowed during Receiver Detect	_	_	_	600	mV
T _{TX-IDLE-MIN}	Min. time in Electrical Idle	-	20	—	_	ns
T _{TX-IDLE-SET-TO-IDLE}	Max. time from El Order Set to valid Electrical Idle	_	_	_	8	ns
T _{TX-IDLE-TO-DIFF-DATA}	Max. time from Electrical Idle to valid differential output	_	_	_	8	ns
L _{TX-SKEW}	Lane-to-lane output skew	-	_	—		ps



Table 3.36. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
RL _{RX_DIFF}	Differential return loss	From 100 MHz to 2.5 GHz	10	—	—	dB
RL _{RX_CM}	Common mode return loss	From 100 MHz to 2.5 GHz	6	-	—	dB
Z _{RX_DIFF}	Differential termination resistance	_	80	100	120	Ω
J _{RX_DJ} ^{2, 3, 4}	Deterministic jitter tolerance (peak-to-peak)	_	—	-	0.37	UI
J _{RX_RJ} ^{2, 3, 4}	Random jitter tolerance (peak-to-peak)	_	—	—	0.18	UI
J _{RX_SJ} ^{2, 3, 4}	Sinusoidal jitter tolerance (peak-to-peak)	—	_	_	0.10	UI
J _{RX_TJ} ^{1, 2, 3, 4}	Total jitter tolerance (peak-to-peak)	_	—	—	0.65	UI
T _{RX_EYE}	Receiver eye opening	—	0.35	—	-	UI

Notes:

- 1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter.
- 2. Jitter values are measured with each high-speed input AC coupled into a 50 Ω impedance.
- 3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
- 4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

3.29. Gigabit Ethernet/SGMII(1.25Gbps)/CPRI LV E.12 Electrical and Timing Characteristics

3.29.1. AC and DC Characteristics

Table 3.37. Transmit

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
T _{RF}	Differential rise/fall time	20% to 80%	-	80	—	ps
Z _{TX_DIFF_DC}	Differential impedance	—	80	100	120	Ω
J _{TX_DDJ} ^{2, 3}	Output data deterministic jitter	-	-	_	0.10	UI
J _{TX_TJ} ^{1, 2, 3}	Total output data jitter	-	1	—	0.24	UI

Notes:

1. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.

2. Jitter values are measured with each CML output AC coupled into a 50 Ω impedance (100 Ω differential impedance).

3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

Table 3.38. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min	Тур	Max	Unit
RL _{RX_DIFF}	Differential return loss	From 100 MHz to 1.25 GHz	10	-	—	dB
RL _{RX_CM}	Common mode return loss	From 100 MHz to 1.25 GHz	6	-	—	dB
Z _{RX_DIFF}	Differential termination resistance	-	80	100	120	Ω
J _{RX_DJ} ^{1, 2, 3, 4}	Deterministic jitter tolerance (peak-to-peak)	-	_	-	0.34	UI
J _{RX_RJ} ^{1, 2, 3, 4}	Random jitter tolerance (peak-to-peak)	-	—	-	0.26	UI
J _{RX_SJ} ^{1, 2, 3, 4}	Sinusoidal jitter tolerance (peak-to-peak)	-	—	-	0.11	UI
J _{RX_TJ} ^{1, 2, 3, 4}	Total jitter tolerance (peak-to-peak)	—	—	-	0.71	UI
T _{RX_EYE}	Receiver eye opening	—	0.29	—	—	UI

Notes:

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter.

- 2. Jitter values are measured with each high-speed input AC coupled into a 50 Ω impedance.
- 3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
- 4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

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*The CFG pins are normally static (hardwired).









4. Pinout Information

4.1. Signal Descriptions

Signal Name	I/O	Description
General Purpose		
P[L/R] [Group Number]_[A/B/C/D]	1/0	 [L/R] indicates the L (Left), or R (Right) edge of the device. [Group Number] indicates the PIO [A/B/C/D] group. [A/B/C/D] indicates the PIO within the PIC to which the pad is connected. Some of these user-programmable pins are shared with special function pins. These pins, when not used as special purpose pins, can be programmed as I/Os for user logic. During configuration the user-programmable I/Os are tristated with an internal pull-down resistor enabled. If any pin is not used (or not bonded to a package pin), it is tristated and default to have pull-down enabled after configuration. PIO A and B are grouped as a pair, and PIO C and D are group as a pair. Each pair supports true LVDS differential input buffer. Only PIO A and B pair supports true LVDS differential output buffer. Each A/B and C/D pair supports programmable on/off differential input termination of 100 Ω.
P[T/B][Group Number]_[A/B]	I/O	 [T/B] indicates the T (top) or B (bottom) edge of the device. [Group Number] indicates the PIO [A/B] group. [A/B] indicates the PIO within the PIC to which the pad is connected. Some of these user-programmable pins are shared with sysConfig pins. These pins, when not used as configuration pins, can be programmed as I/Os for user logic. During configuration, the pins not used in configuration are tristated with an internal pull-down resistor enabled. If any pin is not used (or not bonded to a package pin), it is tristated and default to have pull-down enabled after configuration. PIOs on top and bottom do not support differential input signaling or true LVDS output signaling, but it can support emulated differential output buffer. PIO A/B forms a pair of emulated differential output buffer.
GSRN		Global RESET signal (active low). Any I/O pin can be GSRN.
NC	_	No connect.
RESERVED	_	This pin is reserved and should not be connected to anything on the board.
GND	_	Ground. Dedicated pins.
V _{cc}	_	Power supply pins for core logic. Dedicated pins. V _{CC} = 1.1 V (ECP5), 1.2 V (ECP5UM5G)
Vccaux	-	Auxiliary power supply pin. This dedicated pin powers all the differential and referenced input buffers. $V_{CCAUX} = 2.5 V$.
V _{CCIOx}	_	Dedicated power supply pins for I/O bank x. V_{CCIO8} is used for configuration and JTAG.
VREF1_x	-	Reference supply pins for I/O bank x. Pre-determined shared pin in each bank are assigned as VREF1 input. When not used, they may be used as I/O pins.
PLL, DLL and Clock Functions	1	
[LOC][_GPLL[T, C]_IN	I	General Purpose PLL (GPLL) input pads: [LOC] = ULC, LLC, URC and LRC, T = true and C = complement. These pins are shared I/O pins. When not configured as GPLL input pads, they can be used as general purpose I/O pins.
GR_PCLK[Bank][num]	I	General Routing Signals in Banks 0, 1, 2, 3, 4, 6 and 7. There are two in each bank ([num] = 0, 1). Refer to ECP5 sysClock PLL/DLL Design and Usage Guide (TN1263). These pins are shared I/O pins. When not configured as GR pins, they can be used as general purpose I/O pins.
PCLK[T/C][Bank]_[num]	I/O	General Purpose Primary CLK pads: [T/C] = True/Complement, [Bank] = (0, 1, 2, 3, 6 and 7). There are two in each bank ([num] = 0, 1). These are shared I/ O pins. When not configured as PCLK pins, they can be used as general purpose I/O pins.

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4.2. PICs and DDR Data (DQ) Pins Associated with the DDR Strobe (DQS) Pin

PICs Associated with DQS Strobe	PIO within PIC	DDR Strobe (DQS) and Data (DQ) Pins
	For Left and Right Edges of the Device Only	
	А	DQ
	В	DQ
	С	DQ
	D	DQ
	А	DQ
P[L/R] [n-3]	В	DQ
	С	DQ
	D	DQ
	А	DQS (P)
	В	DQS (N)
	С	DQ
	D	DQ
	А	DQ
	В	DQ
רניהן [11+3]	С	DQ
	D	DQ

Note: "n" is a row PIC number.

4.3. **Pin Information Summary**

4.3.1. **LFE5UM/LFE5UM5G**

Pin Information Summary	LFE5 LFE5UI	5UM/ M5G-25	LFE5UM/LFE5UM5G-45			LFE5UM/LFE5UM5G-85				
Pin Type	285 csfBG	381 caBGA	285 csfBGA	381 caBG	554 caBGA	285 csfBGA	381 caBG	554 caBGA	756 caBGA	
	Bank 0	6	24	6	27	32	6	27	32	56
	Bank 1	6	32	6	33	40	6	33	40	48
	Bank 2	21	32	21	32	32	21	34	32	48
General Purpose	Bank 3	28	32	28	33	48	28	33	48	64
Inputs/Outputs per Bank	Bank 4	0	0	0	0	0	0	0	14	24
	Bank 6	26	32	26	33	48	26	33	48	64
	Bank 7	18	32	18	32	32	18	32	32	48
	Bank 8	13	13	13	13	13	13	13	13	13
Total Single-Ended User I/O		118	197	118	203	245	118	205	259	365
VCC		13	20	13	20	24	13	20	24	36
VCCAUX (Core)		3	4	3	4	9	3	4	9	8
	Bank 0	1	2	1	2	3	1	2	3	4
	Bank 1	1	2	1	2	3	1	2	3	4
	Bank 2	2	3	2	3	4	2	3	4	4
VCCIO	Bank 3	2	3	2	3	3	2	3	3	4
	Bank 4	0	0	0	0	0	0	0	2	2
	Bank 6	2	3	2	3	4	2	3	4	4
	Bank 7	2	3	2	3	3	2	3	3	4
	Bank 8	2	2	2	2	2	2	2	2	2

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Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5U-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	No
LFE5U-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	No
LFE5UM-25F-6MG285C	-6	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-7MG285C	-7	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-6BG381C	-6	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-7BG381C	-7	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-45F-6MG285C	-6	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-7MG285C	-7	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-6BG381C	-6	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-7BG381C	-7	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-6BG554C	-6	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-7BG554C	-7	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	Yes
LFE5UM5G-25F-8MG285C	-8	Lead tree cstBGA	285	Commercial	24	Yes
LFE5UM5G-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM5G-45F-8MG285C	-8	Lead tree cstBGA	285	Commercial	44	Yes
LFE5UM5G-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM5G-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM5G-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes



Revision History

Date	Version	Section	Change Summary
March 2018	1.9	All	Updated formatting and page referencing.
		General Description	Updated Table 1.1. ECP5 and ECP5-5G Family Selection Guide. Added caBGA256 package in LFE5U-45.
		Architecture	Added a row for SGMII in Table 2.13. LFE5UM/LFE5UM5G SERDES Standard Support. Updated footnote #1.
		DC and Switching	Updated Table 3.2. Recommended Operating Conditions.
		Characteristics	Added 2 rows and updated values in Table 3.7. DC Electrical Characteristics.
			Updated Table 3.8. ECP5/ECP5-5G Supply Current (Standby).
			Updated Table 3.11. sysl/O Recommended Operating Conditions.
			Updated Table 3.12. Single-Ended DC Characteristics.
			Updated Table 3.13. LVDS.
			Updated Table 3.14. LVDS25E DC Conditions.
			Updated Table 3.21. ECP5/ECP5-5G Maximum I/O Buffer Speed.
			Updated Table 3.28. Receiver Total Jitter Tolerance Specification.
			Updated header name of section 3.28 CPRI LV E.24/SGMII(2.5Gbps) Electrical and Timing Characteristics.
			Updated header name of section 3.29 Gigabit Ethernet/SCMII(1, 25Gbps)/CPRI LVE 12 Electrical and Timing
			Characteristics
		Pinout Information	Updated table in section 4.3.2 LFE5U.
		Ordering Information	Added table rows in 5.2.1 Commercial.
			Added table rows in 5.2.2 Industrial.
		Supplemental Information	Updated For Further Information section.
November 2017	1.8	General Description	Updated Table 1.1. ECP5 and ECP5-5G Family Selection Guide. Added caBGA256 package in LFE5U-12 and LFE5U-25.



(Continued)

Date	Version	Section	Change Summary
April 2017	1.7	All	Changed document number from DS1044 to FPGA-DS-02012.
		General Description	Updated Features section. Changed "1.1 V core power supply" to "1.1 V core power supply for ECP5, 1.2 V core power supply for ECP5UM5G".
		Architecture	Updated Overview section. Change "The ECP5/ECP5-5G devices use 1.1 V as their core voltage" to "The ECP5 devices use 1.1V, ECP5UM5G devices use 1.2V as their core voltage"
		DC and Switching Characteristics	Updated Table 3.2. Recommended Operating Conditions Added ECP5-5G on VCC to be 1.2V +/- 5% Added ECP5-5G on VCCA to be 1.2V +/- 3% Updated Table 3.8. ECP5/ECP5-5G Supply Current (Standby) Changed "Core Power Supply Current" for ICC on LFE5UM5G devices Changed "SERDES Power Supply Current (Per Dual)" for ICCA on LFE5UM5G devices Updated Table 3.20. Register-to-Register Performance. Remove "(DDR/SDR)" from DSP Function Changed DSP functions to 225 MHz
		Pinout Information	Update Section 4.1 Signal Description. Revised Vcc Description to "Power supply pins for core logic. Dedicated pins. VCC = 1.1 V (ECP5), 1.2 V (ECP5UM5G)"
February 2016	1.6	All	Changed document status from Preliminary to Final.
February 2016		General Description	Updated Features section. Changed "24K to 84K LUTs" to "12K to 84K LUTs". Added LFE5U-12 column to Table 1.1. ECP5 and ECP5-5G Family Selection Guide.
		DC and Switching Characteristics	Updated Power up Sequence section. Identified typical ICC current for specific devices in Table 3.8. ECP5/ECP5-5G Supply Current (Standby). Updated values in Table 3.9. ECP5. Updated values in Table 3.10. ECP5-5G. Added values to -8 Timing column of Table 3.19. Pin-to-Pin Performance. Added values to -8 Timing column of Table 3.20. Register-to-Register Performance. Changed LFE5-45 to All Devices in Table 3.22. ECP5/ECP5-5G External Switching Characteristics. Added table notes to Table 3.31. PCIe (5 Gb/s). Added table note to Table 3.32. CPRI LV2 E.48 Electrical and Timing Characteristics.
		Pinout Information	Added LFE5U-12 column to the table in LFE5U section.
		Ordering Information	Updated LFE5U in ECP5/ECP5-5G Part Number Description section: added 12 F = 12K LUTs to Logic Capacity. Added LFE5U-12F information to Ordering Part Numbers section.